

Notice of References Cited	Application/Control No. 10/785,618		Applicant(s)/Patent Under Reexamination LOOK, CHRISTOPHER M.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,130,837 A	07-1992	Kitamura et al.	398/37
*	B	US-5,539,564 A	07-1996	Kumozaki et al.	398/2
*	C	US-5,559,622 A	09-1996	Huber et al.	398/5
*	D	US-5,594,581 A	01-1997	Alphonsus, Justin E. J.	398/6
*	E	US-5,627,837 A	05-1997	Gillett, Mark D.	714/708
*	F	US-6,307,653 B1	10-2001	Bala et al.	398/2
*	G	US-2001/0046074 A1	11-2001	Kakizaki et al.	359/110
*	H	US-2002/0018616 A1	02-2002	Li, Ming-Jun	385/24
*	I	US-2002/0021659 A1	02-2002	Meijen et al.	370/217
*	J	US-2002/0044315 A1	04-2002	Sugawara et al.	359/110
*	K	US-2002/0080440 A1	06-2002	Li et al.	359/110
*	L	US-2002/0118410 A1	08-2002	Manganini et al.	359/110
*	M	US-6,433,900 B1	08-2002	Kuroyanagi et al.	398/19

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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NON-PATENT DOCUMENTS

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	U	
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,477,288 B1	11-2002	Sato, Kouki	385/16
*	B	US-6,556,319 B2	04-2003	Feinberg et al.	398/5
*	C	US-2003/0180047 A1	09-2003	Way et al.	398/59
*	D	US-6,721,502 B1	04-2004	Al-Salameh et al.	398/3
*	E	US-6,754,449 B2	06-2004	Chang et al.	398/51
*	F	US-2004/0105136 A1	06-2004	Feinberg, Lee Daniel	359/020
*	G	US-2004/0114925 A1	06-2004	Berthold et al.	398/045
*	H	US-2004/0141741 A1	07-2004	Palacharla et al.	398/005
*	I	US-6,775,237 B2	08-2004	Soltysiak et al.	370/241
*	J	US-6,771,908 B2	08-2004	Eijk et al.	398/66
*	K	US-2004/0208578 A1	10-2004	Kinoshita et al.	398/083
*	L	US-2004/0208506 A1	10-2004	Kinoshita et al.	398/019
*	M	US-6,819,875 B2	11-2004	Touma, Eisaku	398/177

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,847,743 B2	01-2005	Yamaguchi, Shohei	385/11
*	B	US-6,850,515 B2	02-2005	Chang et al.	370/352
*	C	US-6,868,232 B2	03-2005	Eijk et al.	398/5
*	D	US-6,898,376 B1	05-2005	Gerstel et al.	398/5
*	E	US-2005/0135810 A1	06-2005	Kim et al.	398/072
*	F	US-6,917,759 B2	07-2005	de Boer et al.	398/5
*	G	US-6,934,469 B2	08-2005	Feinberg et al.	398/5
*	H	US-2005/0180316 A1	08-2005	Chan, Frederick Ying-shu	370/216
*	I	US-6,950,215 B2	09-2005	Fant et al.	359/16
*	J	US-6,947,623 B2	09-2005	Ramaswami et al.	385/16
*	K	US-6,980,711 B2	12-2005	Feinberg et al.	385/16
*	L	US-6,983,108 B2	01-2006	Sugawara et al.	398/45
*	M	US-7,099,578 B1	08-2006	Gerstel, Ornan A.	398/5

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,113,698 B1	09-2006	Ryhorchuk et al.	398/10
*	B	US-7,126,908 B1	10-2006	Lu et al.	370/228
*	C	US-7,161,898 B1	01-2007	Mazzurco et al.	370/217
*	D	US-7,174,096 B2	02-2007	Berthold et al.	398/5
*	E	US-7,181,137 B1	02-2007	Tamburello et al.	398/20
*	F	US-7,197,241 B2	03-2007	Weston-Dawkes et al.	398/5
*	G	US-7,242,860 B2	07-2007	Ikeda et al.	398/5
*	H	US-7,283,740 B2	10-2007	Kinoshita et al.	398/5
*	I	US-7,283,748 B2	10-2007	Jung et al.	398/72
*	J	US-2009/0034963 A1	02-2009	Look, Christopher M.	398/5
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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